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[Understanding Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	140
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	176-LQFP
Supplier Device Package	176-TQFP (24x24)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-2tqg176

2 40MX and 42MX FPGA Families

2.1 Features

The following sections list out various features of the 40MX and 42MX FPGA family devices.

2.1.1 High Capacity

- Single-Chip ASIC Alternative
- 3,000 to 54,000 System Gates
- Up to 2.5 kbits Configurable Dual-Port SRAM
- Fast Wide-Decode Circuitry
- Up to 202 User-Programmable I/O Pins

2.1.2 High Performance

- 5.6 ns Clock-to-Out
- 250 MHz Performance
- 5 ns Dual-Port SRAM Access
- 100 MHz FIFOs
- 7.5 ns 35-Bit Address Decode

2.1.3 HiRel Features

- Commercial, Industrial, Automotive, and Military Temperature Plastic Packages
- Commercial, Military Temperature, and MIL-STD-883 Ceramic Packages
- QML Certification
- Ceramic Devices Available to DSCC SMD

2.1.4 Ease of Integration

- Mixed-Voltage Operation (5.0 V or 3.3 V for core and I/Os), with PCI-Compliant I/Os
- Up to 100% Resource Utilization and 100% Pin Locking
- Deterministic, User-Controllable Timing
- Unique In-System Diagnostic and Verification Capability with Silicon Explorer II
- Low Power Consumption
- IEEE Standard 1149.1 (JTAG) Boundary Scan Testing

2.2 Product Profile

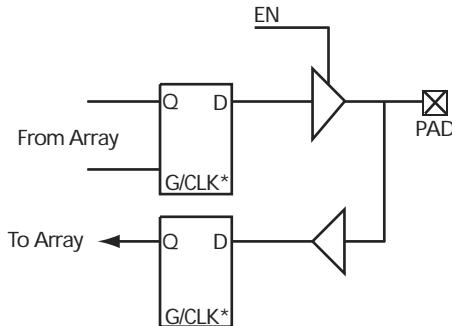
The following table gives the features of the products.

Table 1 • Product profile

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
Capacity						
System Gates	3,000	6,000	14,000	24,000	36,000	54,000
SRAM Bits	—	—	—	—	—	2,560
Logic Modules						
Sequential	—	—	348	624	954	1,230
Combinatorial	295	547	336	608	912	1,184
Decode	—	—	—	—	24	24
Clock-to-Out						
	9.5 ns	9.5 ns	5.6 ns	6.1 ns	6.1 ns	6.3 ns
SRAM Modules (64x4 or 32x8)						
	—	—	—	—	—	10
Dedicated Flip-Flops						
	—	—	348	624	954	1,230

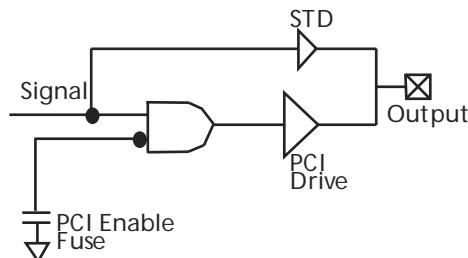
Designer software development tools provide a design library of I/O macro functions that can implement all I/O configurations supported by the MX FPGAs.

Figure 10 • 42MX I/O Module



Note: *Can be configured as a Latch or D Flip-Flop (Using C-Module)

Figure 11 • PCI Output Structure of A42MX24 and A42MX36 Devices



3.3 Other Architectural Features

The following sections cover other architectural features of 40MX and 42MX FPGAs.

3.3.1 Performance

MX devices can operate with internal clock frequencies of 250 MHz, enabling fast execution of complex logic functions. MX devices are live on power-up and do not require auxiliary configuration devices and thus are an optimal platform to integrate the functionality contained in multiple programmable logic devices. In addition, designs that previously would have required a gate array to meet performance can be integrated into an MX device with improvements in cost and time-to-market. Using timing-driven place-and-route (TDPR) tools, designers can achieve highly deterministic device performance.

3.3.2 User Security

Microsemi FuseLock provides robust security against design theft. Special security fuses are hidden in the fabric of the device and protect against unauthorized users attempting to access the programming and/or probe interfaces. It is virtually impossible to identify or bypass these fuses without damaging the device, making Microsemi antifuse FPGAs protected with the highest level of security available from both invasive and noninvasive attacks.

Special security fuses in 40MX devices include the Probe Fuse and Program Fuse. The former disables the probing circuitry while the latter prohibits further programming of all fuses, including the Probe Fuse. In 42MX devices, there is the Security Fuse which, when programmed, both disables the probing circuitry and prohibits further programming of the device.

3.3.3 Programming

Device programming is supported through the Silicon Sculptor series of programmers. Silicon Sculptor is a compact, robust, single-site and multi-site device programmer for the PC. With standalone software, Silicon Sculptor is designed to allow concurrent programming of multiple units from the same PC.

- VCCA = Power supply in volts (V)
- F = Switching frequency in megahertz (MHz)

3.4.4 Equivalent Capacitance

Equivalent capacitance is calculated by measuring ICCactive at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of VCC. Equivalent capacitance is frequency-independent, so the results can be used over a wide range of operating conditions. Equivalent capacitance values are shown below.

3.4.5 C_{EQ} Values for Microsemi MX FPGAs

Modules (C_{EQM})3.5

Input Buffers (C_{EQI})6.9

Output Buffers (C_{EQO})18.2

Routed Array Clock Buffer Loads (C_{EQCR})1.4

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. The equation below shows a piece-wise linear summation over all components.

$$\text{Power} = \text{VCCA}^2 * [(m * C_{EQM} * f_m)_{\text{modules}} + (n * C_{EQI} * f_n)_{\text{inputs}} + (p * (C_{EQO} + C_L) * f_p)_{\text{outputs}} + \\ 0.5 * (q_1 * C_{EQCR} * f_{q1})_{\text{routed_Clk1}} + (r_1 * f_{q1})_{\text{routed_Clk1}} + \\ 0.5 * (q_2 * C_{EQCR} * f_{q2})_{\text{routed_Clk2}} + (r_2 * f_{q2})_{\text{routed_Clk2}}(2)]$$

EQ 3

where:

m = Number of logic modules switching at frequency f_m

n = Number of input buffers switching at frequency f_n

p = Number of output buffers switching at frequency f_p

q₁ = Number of clock loads on the first routed array clock

q₂ = Number of clock loads on the second routed array clock

r₁ = Fixed capacitance due to first routed array clock

r₂ = Fixed capacitance due to second routed array clock

C_{EQM} = Equivalent capacitance of logic modules in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of routed array clock in pF

C_L = Output load capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average first routed array clock rate in MHz

3.8.1 3.3 V LVTTL Electrical Specifications

Table 19 • 3.3V LVTTL Electrical Specifications

Symbol	Parameter	Commercial		Commercial -F		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	IOH = -4 mA	2.15		2.15		2.4		2.4		V
VOL ¹	IOL = 6 mA		0.4		0.4		0.48		0.48	V
VIL		-0.3	0.8	-0.3	0.8	-0.3	0.8	-0.3	0.8	V
VIH (40MX)		2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIH (42MX)		2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	V
IIL			-10		-10		-10		-10	µA
IIH			-10		-10		-10		-10	µA
Input Transition Time, T _R and T _F			500		500		500		500	ns
C _{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, ICC ²	A40MX02, A40MX04	3		25		10		25		mA
	A42MX09	5		25		25		25		mA
	A42MX16	6		25		25		25		mA
	A42MX24, A42MX36	15		25		25		25		mA
Low-Power Mode Standby Current	42MX devices only	0.5		ICC - 5.0		ICC - 5.0		ICC - 5.0		mA
IIO, I/O source sink current	Can be derived from the <i>IB/S model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)									

1. Only one output tested at a time. VCC/VCCI = min.
2. All outputs unloaded. All inputs = VCC/VCCI or GND.

3.9 Mixed 5.0 V / 3.3 V Operating Conditions (for 42MX Devices Only)

Table 20 • Absolute Maximum Ratings*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	-0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	-0.5 to +7.0	V
VI	Input Voltage	-0.5 to VCCA + 0.5	V
VO	Output Voltage	-0.5 to VCCI + 0.5	V
t _{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device

A sample calculation of the absolute maximum power dissipation allowed for a TQ176 package at commercial temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (\text{°C}) - \text{Max} \cdot \text{ambient temp} \cdot (\text{°C})}{\theta_{ja}(\text{°C/W})} = \frac{150\text{°C} - 70\text{°C}}{(28\text{°C})/\text{W}} = 2.86\text{W}$$

EQ 5

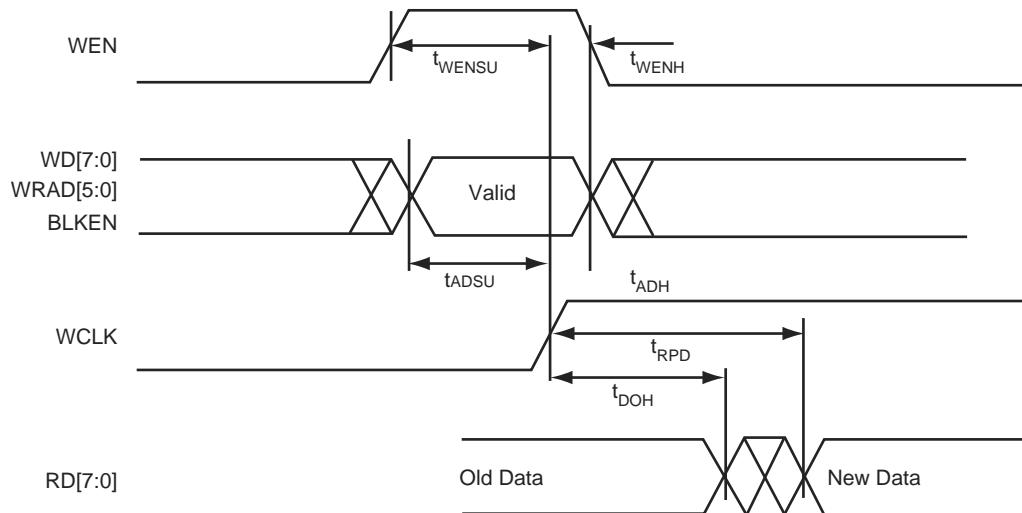
The maximum power dissipation for military-grade devices is a function of θ_{jc} . A sample calculation of the absolute maximum power dissipation allowed for CQFP 208-pin package at military temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (\text{°C}) - \text{Max} \cdot \text{ambient temp} \cdot (\text{°C})}{\theta_{jc}(\text{°C/W})} = \frac{150\text{°C} - 125\text{°C}}{(6.3\text{°C})/\text{W}} = 3.97\text{W}$$

EQ 6

Table 27 • Package Thermal Characteristics

Plastic Packages	Pin Count	θ_{jc}	θ_{ja}			Units
			Still Air	1.0 m/s 200 ft/min.	2.5 m/s 500 ft/min.	
Plastic Quad Flat Pack	100	12.0	27.8	23.4	21.2	°C/W
Plastic Quad Flat Pack	144	10.0	26.2	22.8	21.1	°C/W
Plastic Quad Flat Pack	160	10.0	26.2	22.8	21.1	°C/W
Plastic Quad Flat Pack	208	8.0	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack	240	8.5	25.6	22.3	20.8	°C/W
Plastic Leaded Chip Carrier	44	16.0	20.0	24.5	22.0	°C/W
Plastic Leaded Chip Carrier	68	13.0	25.0	21.0	19.4	°C/W
Plastic Leaded Chip Carrier	84	12.0	22.5	18.9	17.6	°C/W
Thin Plastic Quad Flat Pack	176	11.0	24.7	19.9	18.0	°C/W
Very Thin Plastic Quad Flat Pack	80	12.0	38.2	31.9	29.4	°C/W
Very Thin Plastic Quad Flat Pack	100	10.0	35.3	29.4	27.1	°C/W
Plastic Ball Grid Array	272	3.0	18.3	14.9	13.9	°C/W
Ceramic Packages						
Ceramic Pin Grid Array	132	4.8	25.0	20.6	18.7	°C/W
Ceramic Quad Flat Pack	208	2.0	22.0	19.8	18.0	°C/W
Ceramic Quad Flat Pack	256	2.0	20.0	16.5	15.0	°C/W

Figure 33 • 42MX SRAM Asynchronous Read Operation—Type 2 (Write Address Controlled)

3.10.7 Predictable Performance: Tight Delay Distributions

Propagation delay between logic modules depends on the resistive and capacitive loading of the routing tracks, the interconnect elements, and the module inputs being driven. Propagation delay increases as the length of routing tracks, the number of interconnect elements, or the number of inputs increases.

From a design perspective, the propagation delay can be statistically correlated or modeled by the fanout (number of loads) driven by a module. Higher fanout usually requires some paths to have longer routing tracks.

The MX FPGAs deliver a tight fanout delay distribution, which is achieved in two ways: by decreasing the delay of the interconnect elements and by decreasing the number of interconnect elements per path.

Microsemi's patented antifuse offers a very low resistive/capacitive interconnect. The antifuses, fabricated in 0.45 µm lithography, offer nominal levels of 100 Ω resistance and 7.0 fF capacitance per antifuse.

MX fanout distribution is also tight due to the low number of antifuses required for each interconnect path. The proprietary architecture limits the number of antifuses per path to a maximum of four, with 90 percent of interconnects using only two antifuses.

3.11 Timing Characteristics

Device timing characteristics fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all MX devices. Internal routing delays are device-dependent; actual delays are not determined until after place-and-route of the user's design is complete. Delay values may then be determined by using the Designer software utility or by performing simulation with post-layout delays.

3.11.1 Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing critical paths. Critical nets are determined by net property assignment in Microsemi's Designer software prior to placement and routing. Up to 6% of the nets in a design may be designated as critical.

3.11.2 Long Tracks

Some nets in the design use long tracks, which are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes four antifuse connections, which increase capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks add

Table 34 • A40MX02 Timing Characteristics (Nominal 5.0 V Operation) (continued)
(Worst-Case Commercial Conditions, VCC = 4.75 V, TJ = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays											
t _{INYH}	Pad-to-Y HIGH		0.7		0.8		0.9		1.1		1.5 ns
t _{INYL}	Pad-to-Y LOW		0.6		0.7		0.8		1.0		1.3 ns
Input Module Predicted Routing Delays¹											
t _{IRD1}	FO = 1 Routing Delay		2.1		2.4		2.2		3.2		4.5 ns
t _{IRD2}	FO = 2 Routing Delay		2.6		3.0		3.4		4.0		5.6 ns
t _{IRD3}	FO = 3 Routing Delay		3.1		3.6		4.1		4.8		6.7 ns
t _{IRD4}	FO = 4 Routing Delay		3.6		4.2		4.8		5.6		7.8 ns
t _{IRD8}	FO = 8 Routing Delay		5.7		6.6		7.5		8.8		12.4 ns
Global Clock Network											
t _{CKH}	Input Low to HIGH	FO = 16	4.6		5.3		6.0		7.0		9.8 ns
		FO = 128	4.6		5.3		6.0		7.0		9.8
t _{CKL}	Input High to LOW	FO = 16	4.8		5.6		6.3		7.4		10.4 ns
		FO = 128	4.8		5.6		6.3		7.4		10.4
t _{PWH}	Minimum Pulse Width HIGH	FO = 16	2.2		2.6		2.9		3.4		4.8 ns
		FO = 128	2.4		2.7		3.1		3.6		5.1
t _{PWL}	Minimum Pulse Width LOW	FO = 16	2.2		2.6		2.9		3.4		4.8 ns
		FO = 128	2.4		2.7		3.01		3.6		5.1
t _{CKSW}	Maximum Skew	FO = 16	0.4		0.5		0.5		0.6		0.8 ns
		FO = 128	0.5		0.6		0.7		0.8		1.2
t _P	Minimum Period	FO = 16	4.7		5.4		6.1		7.2		10.0 ns
		FO = 128	4.8		5.6		6.3		7.5		10.4
f _{MAX}	Maximum Frequency	FO = 16	188		175		160		139		83 MHz
		FO = 128	181		168		154		134		80

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing⁴											
t _{DH}	Data-to-Pad HIGH		5.5	6.4	7.2	8.5	11.9	ns			
t _{DHL}	Data-to-Pad LOW		4.8	5.5	6.2	7.3	10.2	ns			
t _{ENZH}	Enable Pad Z to HIGH		4.7	5.5	6.2	7.3	10.2	ns			
t _{ENZL}	Enable Pad Z to LOW		6.8	7.9	8.9	10.5	14.7	ns			
t _{ENHZ}	Enable Pad HIGH to Z		11.1	12.8	14.5	17.1	23.9	ns			
t _{ENLZ}	Enable Pad LOW to Z		8.2	9.5	10.7	12.6	17.7	ns			
d _{TLH}	Delta LOW to HIGH		0.05	0.05	0.06	0.07	0.10	ns/pF			
d _{THL}	Delta HIGH to LOW		0.03	0.03	0.04	0.04	0.06	ns/pF			

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro.
4. Delays based on 35 pF loading.

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays¹											
t _{PD1}	Single Module		1.2	1.3	1.5	1.8	2.5	ns			
t _{CO}	Sequential Clock-to-Q		1.3	1.4	1.6	1.9	2.7	ns			
t _{GO}	Latch G-to-Q		1.2	1.4	1.6	1.8	2.6	ns			
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.2	1.6	1.8	2.1	2.9	ns			
Logic Module Predicted Routing Delays²											
t _{RD1}	FO = 1 Routing Delay		0.7	0.8	0.9	1.0	1.4	ns			
t _{RD2}	FO = 2 Routing Delay		0.9	1.0	1.2	1.4	1.9	ns			
t _{RD3}	FO = 3 Routing Delay		1.2	1.3	1.5	1.7	2.4	ns			
t _{RD4}	FO = 4 Routing Delay		1.4	1.5	1.7	2.0	2.9	ns			
t _{RD8}	FO = 8 Routing Delay		2.3	2.6	2.9	3.4	4.8	ns			
Logic Module Sequential Timing^{3, 4}											
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up		0.3	0.4	0.4	0.5	0.7	ns			
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0	0.0	0.0	0.0	0.0	0.0	ns			
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.4	0.5	0.5	0.6	0.8	ns				
t _{HEN} A	Flip-Flop (Latch) Enable Hold	0.0	0.0	0.0	0.0	0.0	0.0	ns			
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.4	3.8	4.3	5.0	7.0	ns				

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, TJ = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays												
t _{INYH}	Pad-to-Y HIGH			1.0	1.2	1.3	1.6	2.2	ns			
t _{INYL}	Pad-to-Y LOW			0.8	0.9	1.0	1.2	1.7	ns			
t _{INGH}	G to Y HIGH			1.3	1.4	1.6	1.9	2.7	ns			
t _{INGL}	G to Y LOW			1.3	1.4	1.6	1.9	2.7	ns			
Input Module Predicted Routing Delays²												
t _{IRD1}	FO = 1 Routing Delay			2.0	2.2	2.5	3.0	4.2	ns			
t _{IRD2}	FO = 2 Routing Delay			2.3	2.5	2.9	3.4	4.7	ns			
t _{IRD3}	FO = 3 Routing Delay			2.5	2.8	3.2	3.7	5.2	ns			
t _{IRD4}	FO = 4 Routing Delay			2.8	3.1	3.5	4.1	5.7	ns			
t _{IRD8}	FO = 8 Routing Delay			3.7	4.1	4.7	5.5	7.7	ns			
Global Clock Network												
t _{CKH}	Input LOW to HIGH	FO = 32		2.4	2.7	3.0	3.6	5.0	ns			
		FO = 256		2.7	3.0	3.4	4.0	5.5	ns			
t _{CKL}	Input HIGH to LOW	FO = 32		3.5	3.9	4.4	5.2	7.3	ns			
		FO = 256		3.9	4.3	4.9	5.7	8.0	ns			
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	1.2	1.4	1.5	1.8	2.5	ns				
		FO = 256	1.3	1.5	1.7	2.0	2.7	ns				
t _{PWL}	Minimum Pulse Width LOW	FO = 32	1.2	1.4	1.5	1.8	2.5	ns				
		FO = 256	1.3	1.5	1.7	2.0	2.7	ns				
t _{CKSW}	Maximum Skew	FO = 32		0.3	0.3	0.4	0.5	0.6	ns			
		FO = 256		0.3	0.3	0.4	0.5	0.6	ns			
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0	0.0	0.0	0.0	0.0	0.0	ns			
		FO = 256	0.0	0.0	0.0	0.0	0.0	0.0	ns			
t _{HEXT}	Input Latch External Hold	FO = 32	2.3	2.6	3.0	3.5	4.9	ns				
		FO = 256	2.2	2.4	3.3	3.9	5.5	ns				
t _P	Minimum Period	FO = 32	3.4	3.7	4.0	4.7	7.8	ns				
		FO = 256	3.7	4.1	4.5	5.2	8.6	ns				
f _{MAX}	Maximum Frequency	FO = 32		296	269	247	215	129	MHz			
		FO = 256		268	244	224	195	117	MHz			

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, TJ = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{RD4}	FO = 4 Routing Delay			1.9		2.1		2.4		2.9		4.0 ns
t _{RD8}	FO = 8 Routing Delay			3.2		3.6		4.1		4.8		6.7 ns
Logic Module Sequential Timing^{3, 4}												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	0.5		0.5		0.6		0.7		0.9		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.6		0.6		0.7		0.8		1.2		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		4.7		5.3		6.0		7.0		9.8	ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		6.2		6.9		7.8		9.2		12.9	ns
t _A	Flip-Flop Clock Input Period	5.0		5.6		6.2		7.1		9.9		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{NSU}	Input Buffer Latch Set-Up	0.3		0.3		0.3		0.4		0.6		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Set-Up	0.3		0.3		0.3		0.4		0.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency		161		146		135		117		70	MHz

Table 42 • A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, TJ = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing⁵												
t _{DH}	Data-to-Pad HIGH	2.4		2.7		3.1		3.6		5.1		ns
t _{DHL}	Data-to-Pad LOW	2.8		3.2		3.6		4.2		5.9		ns
t _{ENZH}	Enable Pad Z to HIGH	2.5		2.8		3.2		3.8		5.3		ns
t _{ENZL}	Enable Pad Z to LOW	2.8		3.1		3.5		4.2		5.9		ns
t _{ENHZ}	Enable Pad HIGH to Z	5.2		5.7		6.5		7.6		10.7		ns
t _{ENLZ}	Enable Pad LOW to Z	4.8		5.3		6.0		7.1		9.9		ns
t _{GLH}	G-to-Pad HIGH	2.9		3.2		3.6		4.3		6.0		ns
t _{GHL}	G-to-Pad LOW	2.9		3.2		3.6		4.3		6.0		ns
t _{LSU}	I/O Latch Output Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O	5.6		6.1		6.9		8.1		11.4		ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O	10.6		11.8		13.4		15.7		22.0		ns
d _{TLH}	Capacitive Loading, LOW to HIGH	0.04		0.04		0.04		0.05		0.07		ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW	0.03		0.03		0.03		0.04		0.06		ns/pF

Table 43 • A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, TJ = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed	
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.
Logic Module Sequential Timing^{3,4}											
t _{CO}	Flip-Flop Clock-to-Output		2.1		2.0		2.3		2.7		3.7 ns
t _{GO}	Latch Gate-to-Output		3.4		1.9		2.1		2.5		3.4 ns
t _{SUD}	Flip-Flop (Latch) Set-Up Time	0.4		0.5		0.6		0.7		0.9	ns
t _{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0	ns
t _{RO}	Flip-Flop (Latch) Reset-to-Output		2.0		2.2		2.5		2.9		4.1 ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.6		0.6		0.7		0.8		1.2	ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0	ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		4.6		5.2		5.8		6.9		9.6 ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		6.1		6.8		7.7		9.0		12.6 ns
Input Module Propagation Delays											
t _{INPY}	Input Data Pad-to-Y		1.4		1.6		1.8		2.2		3.0 ns
t _{INGO}	Input Latch Gate-to-Output		1.8		1.9		2.2		2.6		3.6 ns
t _{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0	ns
t _{INSU}	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4	ns
t _{ILA}	Latch Active Pulse Width		6.5		7.3		8.2		9.7		13.5 ns

Table 49 • PL84

PL84	Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
47	I/O	I/O	I/O	I/O	WD, I/O
48	I/O	I/O	I/O	I/O	
49	I/O	GND	GND	GND	
50	I/O	I/O	I/O	I/O	WD, I/O
51	I/O	I/O	I/O	I/O	WD, I/O
52	I/O	SDO, I/O	SDO, I/O	SDO, TDO, I/O	
53	I/O	I/O	I/O	I/O	
54	I/O	I/O	I/O	I/O	
55	I/O	I/O	I/O	I/O	
56	I/O	I/O	I/O	I/O	
57	I/O	I/O	I/O	I/O	
58	I/O	I/O	I/O	I/O	
59	I/O	I/O	I/O	I/O	
60	GND	I/O	I/O	I/O	
61	GND	I/O	I/O	I/O	
62	I/O	I/O	I/O	TCK, I/O	
63	I/O	LP	LP	LP	
64	CLK, I/O	VCCA	VCCA	VCCA	
65	I/O	VCCI	VCCI	VCCI	
66	MODE	I/O	I/O	I/O	
67	VCC	I/O	I/O	I/O	
68	VCC	I/O	I/O	I/O	
69	I/O	I/O	I/O	I/O	
70	I/O	GND	GND	GND	
71	I/O	I/O	I/O	I/O	
72	SDI, I/O	I/O	I/O	I/O	
73	DCLK, I/O	I/O	I/O	I/O	
74	PRA, I/O	I/O	I/O	I/O	
75	PRB, I/O	I/O	I/O	I/O	
76	I/O	SDI, I/O	SDI, I/O	SDI, I/O	
77	I/O	I/O	I/O	I/O	
78	I/O	I/O	I/O	WD, I/O	
79	I/O	I/O	I/O	WD, I/O	
80	I/O	I/O	I/O	WD, I/O	
81	I/O	PRA, I/O	PRA, I/O	PRA, I/O	
82	GND	I/O	I/O	I/O	
83	I/O	CLKA, I/O	CLKA, I/O	CLKA, I/O	

Table 52 • PQ160

PQ160	Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
	95	I/O	I/O	I/O
	96	I/O	I/O	WD, I/O
	97	I/O	I/O	I/O
	98	VCCA	VCCA	VCCA
	99	GND	GND	GND
	100	NC	I/O	I/O
	101	I/O	I/O	I/O
	102	I/O	I/O	I/O
	103	NC	I/O	I/O
	104	I/O	I/O	I/O
	105	I/O	I/O	I/O
	106	I/O	I/O	WD, I/O
	107	I/O	I/O	WD, I/O
	108	I/O	I/O	I/O
	109	GND	GND	GND
	110	NC	I/O	I/O
	111	I/O	I/O	WD, I/O
	112	I/O	I/O	WD, I/O
	113	I/O	I/O	I/O
	114	NC	VCCI	VCCI
	115	I/O	I/O	WD, I/O
	116	NC	I/O	WD, I/O
	117	I/O	I/O	I/O
	118	I/O	I/O	TDI, I/O
	119	I/O	I/O	TMS, I/O
	120	GND	GND	GND
	121	I/O	I/O	I/O
	122	I/O	I/O	I/O
	123	I/O	I/O	I/O
	124	NC	I/O	I/O
	125	GND	GND	GND
	126	I/O	I/O	I/O
	127	I/O	I/O	I/O
	128	I/O	I/O	I/O
	129	NC	I/O	I/O
	130	GND	GND	GND
	131	I/O	I/O	I/O

Table 53 • PQ208

PQ208	Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
	169	I/O	WD, I/O	WD, I/O
	170	I/O	I/O	I/O
	171	NC	I/O	QCLKD, I/O
	172	I/O	I/O	I/O
	173	I/O	I/O	I/O
	174	I/O	I/O	I/O
	175	I/O	I/O	I/O
	176	I/O	WD, I/O	WD, I/O
	177	I/O	WD, I/O	WD, I/O
	178	PRA, I/O	PRA, I/O	PRA, I/O
	179	I/O	I/O	I/O
	180	CLKA, I/O	CLKA, I/O	CLKA, I/O
	181	NC	I/O	I/O
	182	NC	VCCI	VCCI
	183	VCCA	VCCA	VCCA
	184	GND	GND	GND
	185	I/O	I/O	I/O
	186	CLKB, I/O	CLKB, I/O	CLKB, I/O
	187	I/O	I/O	I/O
	188	PRB, I/O	PRB, I/O	PRB, I/O
	189	I/O	I/O	I/O
	190	I/O	WD, I/O	WD, I/O
	191	I/O	WD, I/O	WD, I/O
	192	I/O	I/O	I/O
	193	NC	I/O	I/O
	194	NC	WD, I/O	WD, I/O
	195	NC	WD, I/O	WD, I/O
	196	I/O	I/O	QCLKC, I/O
	197	NC	I/O	I/O
	198	I/O	I/O	I/O
	199	I/O	I/O	I/O
	200	I/O	I/O	I/O
	201	NC	I/O	I/O
	202	VCCI	VCCI	VCCI
	203	I/O	WD, I/O	WD, I/O
	204	I/O	WD, I/O	WD, I/O
	205	I/O	I/O	I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
163	WD, I/O
164	WD, I/O
165	I/O
166	QCLKA, I/O
167	I/O
168	I/O
169	I/O
170	I/O
171	I/O
172	VCCI
173	I/O
174	WD, I/O
175	WD, I/O
176	I/O
177	I/O
178	TDI, I/O
179	TMS, I/O
180	GND
181	VCCA
182	GND
183	I/O
184	I/O
185	I/O
186	I/O
187	I/O
188	I/O
189	I/O
190	I/O
191	I/O
192	VCCI
193	I/O
194	I/O
195	I/O
196	I/O
197	I/O
198	I/O
199	I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
200	I/O
201	I/O
202	I/O
203	I/O
204	I/O
205	I/O
206	VCCA
207	I/O
208	I/O
209	VCCA
210	VCCI
211	I/O
212	I/O
213	I/O
214	I/O
215	I/O
216	I/O
217	I/O
218	I/O
219	VCCA
220	I/O
221	I/O
222	I/O
223	I/O
224	I/O
225	I/O
226	I/O
227	VCCI
228	I/O
229	I/O
230	I/O
231	I/O
232	I/O
233	I/O
234	I/O
235	I/O
236	I/O

Table 55 • VQ80

VQ80		
Pin Number	A40MX02 Function	A40MX04 Function
13	VCC	VCC
14	I/O	I/O
15	I/O	I/O
16	I/O	I/O
17	NC	I/O
18	NC	I/O
19	NC	I/O
20	VCC	VCC
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	GND	GND
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	I/O	I/O
33	VCC	VCC
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	I/O	I/O
39	I/O	I/O
40	I/O	I/O
41	NC	I/O
42	NC	I/O
43	NC	I/O
44	I/O	I/O
45	I/O	I/O
46	I/O	I/O
47	GND	GND
48	I/O	I/O

Table 55 • VQ80

VQ80		
Pin Number	A40MX02 Function	A40MX04 Function
49	I/O	I/O
50	CLK, I/O	CLK, I/O
51	I/O	I/O
52	MODE	MODE
53	VCC	VCC
54	NC	I/O
55	NC	I/O
56	NC	I/O
57	SDI, I/O	SDI, I/O
58	DCLK, I/O	DCLK, I/O
59	PRA, I/O	PRA, I/O
60	NC	NC
61	PRB, I/O	PRB, I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	I/O	I/O
67	I/O	I/O
68	GND	GND
69	I/O	I/O
70	I/O	I/O
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	VCC	VCC
75	I/O	I/O
76	I/O	I/O
77	I/O	I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O

Table 61 • PG132

PG132	
Pin Number	A42MX09 Function
B3	I/O
A2	I/O
C3	DCLK
B5	GNDA
E12	GNDA
J2	GNDA
M9	GNDA
B9	GNDI
C5	GNDI
E11	GNDI
F4	GNDI
J3	GNDI
J11	GNDI
L5	GNDI
L9	GNDI
C9	GNDQ
E3	GNDQ
K12	GNDQ
D7	VCCA
G3	VCCA
G10	VCCA
L7	VCCA
C7	VCCI
G2	VCCI
G11	VCCI
K7	VCCI